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November 2003

N-Channel PowerTrench® MOSFET 80V, **8.9A**, **16m**Ω Features **Applications** • $r_{DS(ON)} = 14m\Omega$ (Typ.), $V_{GS} = 10V$, $I_D = 8.9A$ · Primary switch for Isolated DC/DC converters • Q_{q(tot)} = 31nC (Typ.), V_{GS} = 10V • Distributed Power and Intermediate Bus Architectures Low Miller Charge • High Voltage Synchronous Rectifier for DC Bus Low Q_{RR} Body Diode Converters · Optimized efficiency at high frequencies • UIS Capability (Single Pulse and Repetitive Pulse) Formerly developmental type 82663 **Branding Dash** 5 4 3 6 2 1 8 | **SO-8** MOSFET Maximum Ratings T_A = 25°C unless otherwise noted Symbol Parameter Ratings Units V_{DSS} Drain to Source Voltage 80 v V_{GS} Gate to Source Voltage <u>+2</u>0 V Drain Current 8.9 А I_D 5.6 А Pulsed Figure 4 А E_{AS} Single Pulse Avalanche Energy (Note 1) 515 mJ Power dissipation 2.5 W P_D mW/ºC Derate above 25°C 20 Operating and Storage Temperature -55 to 150 °C T_J, T_{STG} **Thermal Characteristics**

$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case (Note 2)	25	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient at 10 seconds (Note 3)	50	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient at 1000 seconds (Note 3)	85	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity	
FDS3572	FDS3572	SO-8	330mm	12mm	2500 units	

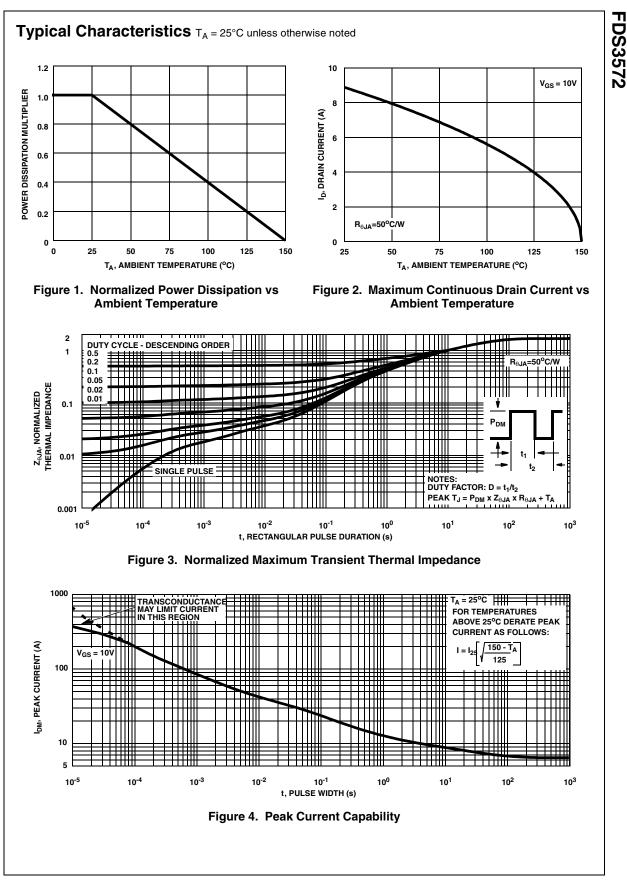
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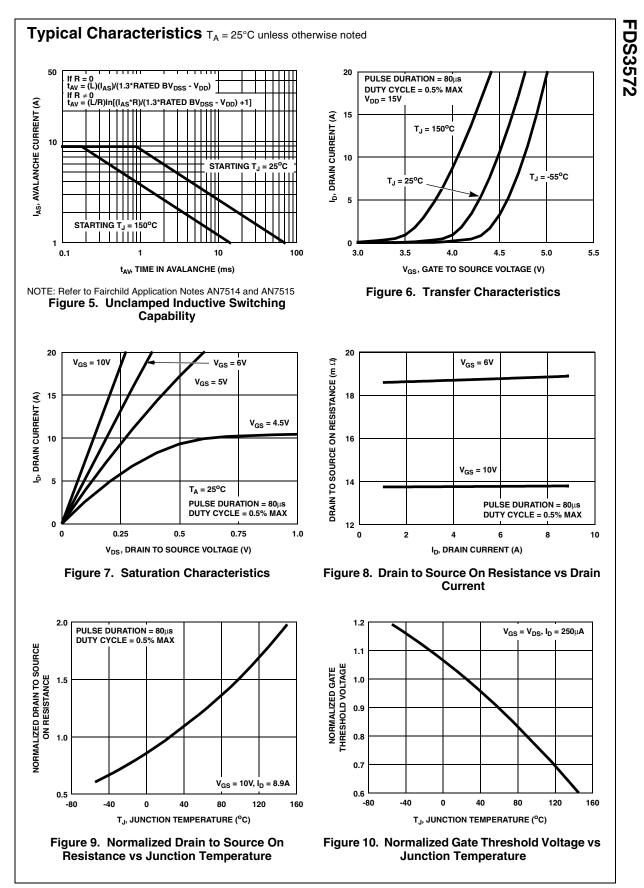
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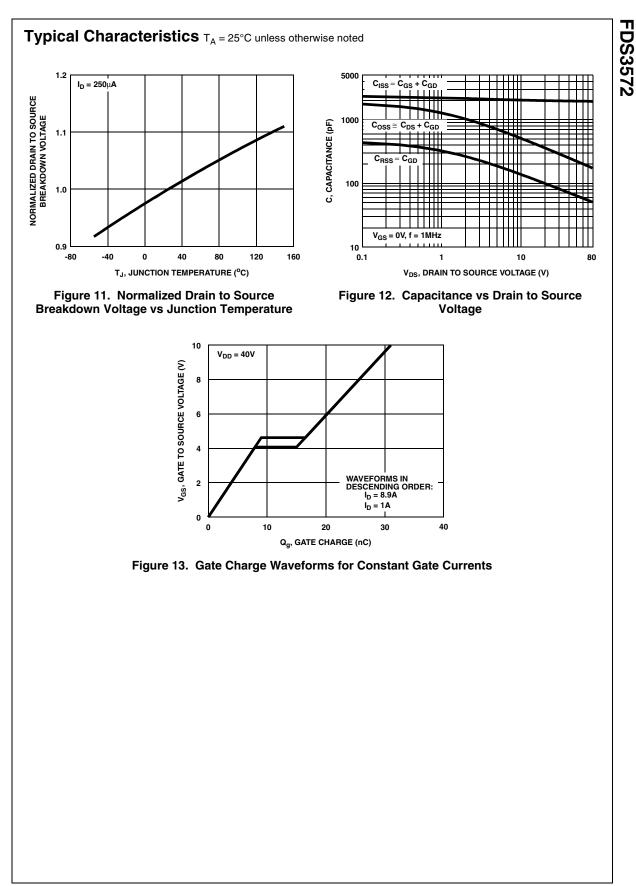
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Chara	cteristics					
B _{VDSS}	Drain to Source Breakdown Voltage	$I_{D} = 250 \mu A, V_{GS} = 0 V$	80	-	-	V
1	Zoro Goto Voltago Drain Current	$V_{DS} = 60V$	-	-	1	
IDSS	Zero Gate Voltage Drain Current	$V_{GS} = 0V \qquad T_A = 150^{\circ}C$	-	-	250	μA
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20V	-	-	±100	nA
On Chara	cteristics					
V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2	-	4	V
		$I_{\rm D} = 8.9$ A, $V_{\rm GS} = 10$ V	-	0.014	0.016	
	Drain to Source On Desistance	$I_{\rm D} = 5.6$ A, $V_{\rm GS} = 6$ V	-	0.019	0.029	Ω
rds(on)	Drain to Source On Resistance	$I_D = 8.9A, V_{GS} = 10V,$ $T_A = 150^{\circ}C$	-	0.027	0.032	
Dynamic	Characteristics					
C _{ISS}	Input Capacitance		-	1990	-	pF
C _{OSS}	Output Capacitance	$-V_{DS} = 25V, V_{GS} = 0V,$	-	320	-	pF
C _{RSS}	Reverse Transfer Capacitance	f = 1MHz	-	85	-	pF
Q _{g(tot)}	Total Gate Charge at 10V	$V_{GS} = 0V$ to 10V	-	31	41	nC
Q _{q(TH)}	Threshold Gate Charge	$V_{GS} = 0V \text{ to } 2V V_{DD} = 40V$	-	4	5.2	nC
Q _{gs}	Gate to Source Gate Charge	I _D = 8.9A	-	9	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau	I _g = 1.0mA	-	5	-	nC
Q _{gd}	Gate to Drain "Miller" Charge		-	7.5	-	nC
Switching	g Characteristics (V _{GS} = 10V)					
t _{ON}	Turn-On Time		-	-	40	ns
t _{d(ON)}	Turn-On Delay Time	-	-	13	-	ns
t _r	Rise Time	V _{DD} = 40V, I _D = 8.9A	-	14	-	ns
t _{d(OFF)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 10\Omega$	-	31	-	ns
t _f	Fall Time	7	-	13	-	ns
t _{OFF}	Turn-Off Time		-	-	67	ns
Drain-Sou	urce Diode Characteristics					
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 8.9A	-	-	1.25	V
▼SD		I _{SD} = 4.3A	-	-	1.0	V
t _{rr}	Reverse Recovery Time	I _{SD} = 8.9A, dI _{SD} /dt= 100A/μs	-	-	50	ns
Q _{RR}	Reverse Recovered Charge	I _{SD} = 8.9A, dI _{SD} /dt= 100A/μs	-	-	70	nC

Notes:
1: Starting T_J = 25°C, L = 21mH, I_{AS} = 7A.
2: R_{θ,JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{θ,JC} is guaranteed by design while R_{θ,JA} is determined by the user's board design.
3: R_{θ,JA} is measured with 1.0 in² copper on FR-4 board

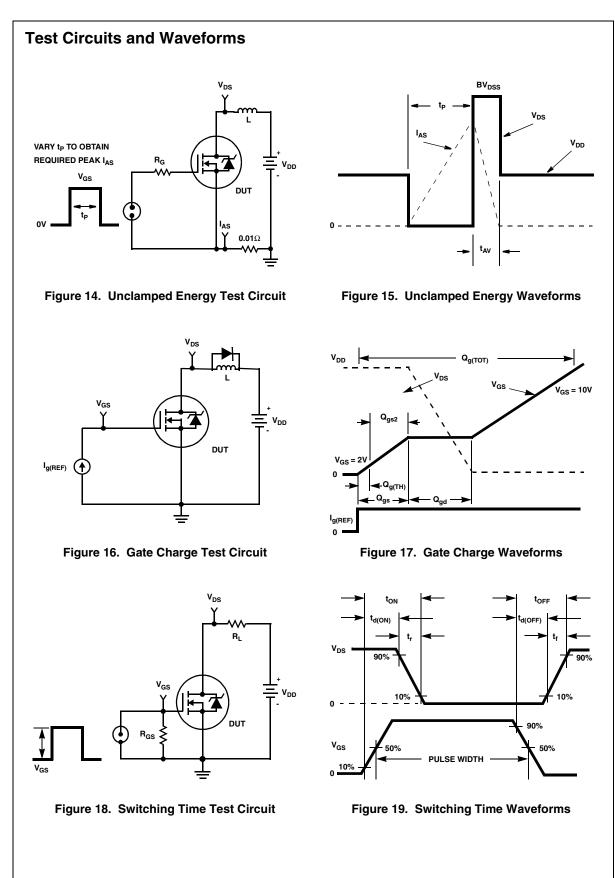
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Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the SO8 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- 1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta,JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized

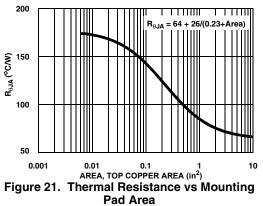
maximum transient thermal impedance curve.

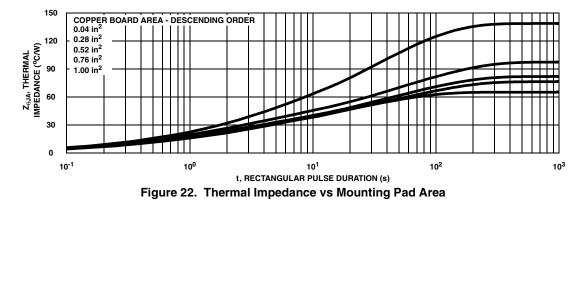
Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2. The area, in square inches is the top copper area including the gate and source pads.

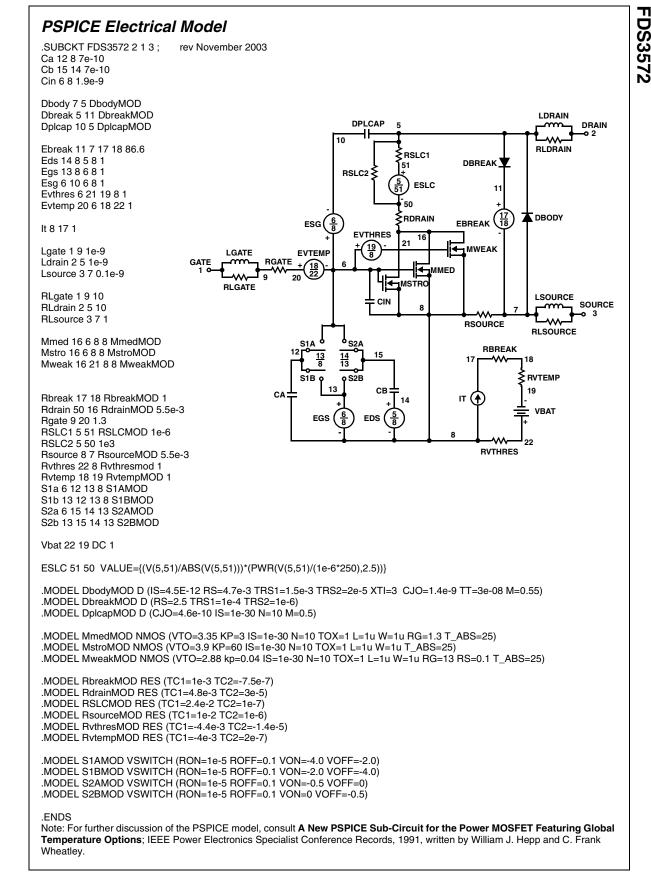
$$R_{\theta JA} = 64 + \frac{26}{0.23 + Area}$$
 (EQ. 2)

The transient thermal impedance $(Z_{\theta,JA})$ is also effected by varied top copper board area. Figure 22 shows the effect of copper pad area on single pulse transient thermal impedance. Each trace represents a copper pad area in square inches corresponding to the descending list in the graph. Spice and SABER thermal models are provided for each of the listed pad areas.

Copper pad area has no perceivable effect on transient thermal impedance for pulse widths less than 100ms. For pulse widths less than 100ms the transient thermal impedance is determined by the die and package. Therefore, CTHERM1 through CTHERM5 and RTHERM1 through RTHERM5 remain constant for each of the thermal models. A listing of the model component values is available in Table 1.

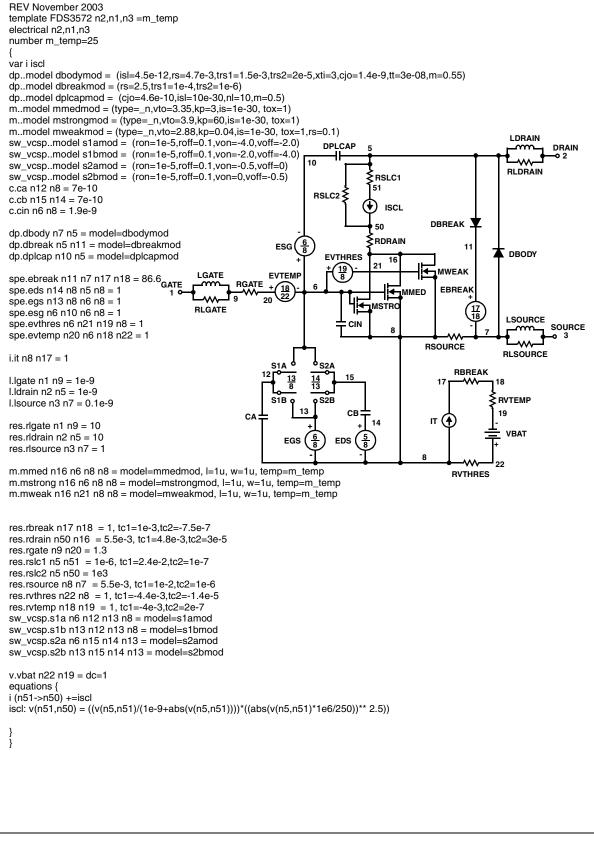


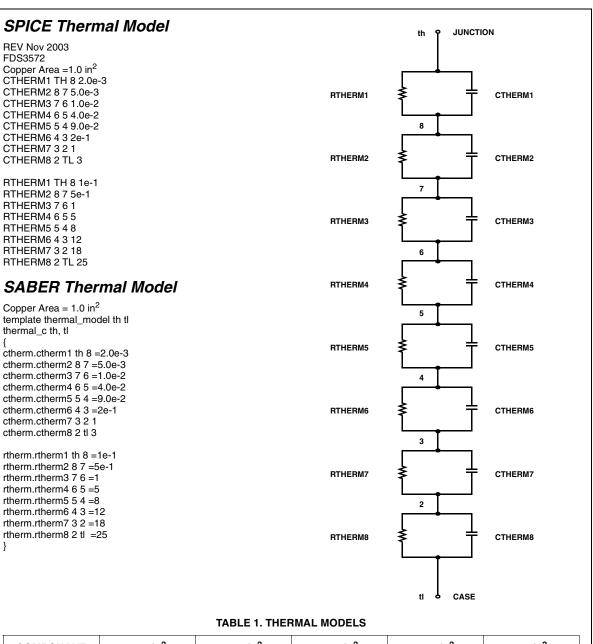




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SABER Electrical Model





COMPONANT	0.04 in ²	0.28 in ²	0.52 in ²	0.76 in ²	1.0 in ²
CTHERM6	1.2e-1	1.5e-1	2.0e-1	2.0e-1	2.0e-1
CTHERM7	0.5	1.0	1.0	1.0	1.0
CTHERM8	1.3	2.8	3.0	3.0	3.0
RTHERM6	26	20	15	13	12
RTHERM7	39	24	21	19	18
RTHERM8	55	38.7	31.3	29.7	25

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CoolFET™	FPS™	MicroFET™	QFET [®]	SuperSOT™-8
CROSSVOLT™	FRFET™	MicroPak™	QS™	SyncFET™
DOME™	GlobalOptoisolator™	MICROWIRE™	QT Optoelectronics [™]	TinyLogic®
EcoSPARK™	GTO™	MSX™	Quiet Series [™]	TINYOPTO™
E ² CMOS [™]	HiSeC™	MSXPro™	RapidConfigure™	TruTranslation™
EnSigna™	I²C™	OCX™	RapidConnect™	UHC™
FACT™	ImpliedDisconnect™	OCXPro™	SILENT SWITCHER®	UltraFET [®]
Across the board	d. Around the world.™	OPTOLOGIC [®]	SMART START™	VCX™
The Power France		OPTOPLANAR™	SPM™	
Programmable A		PACMAN™	Stealth™	
-	-			

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